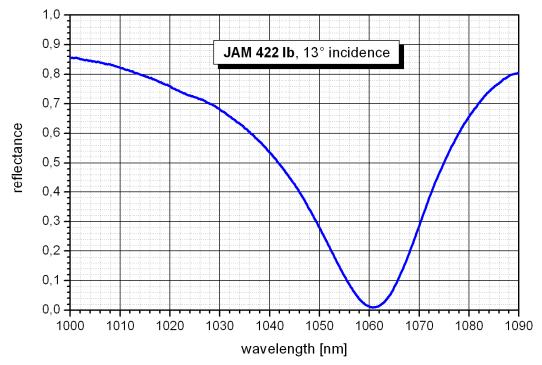


RSAM data sheet RSAM-1064-x, λ = 1064 nm

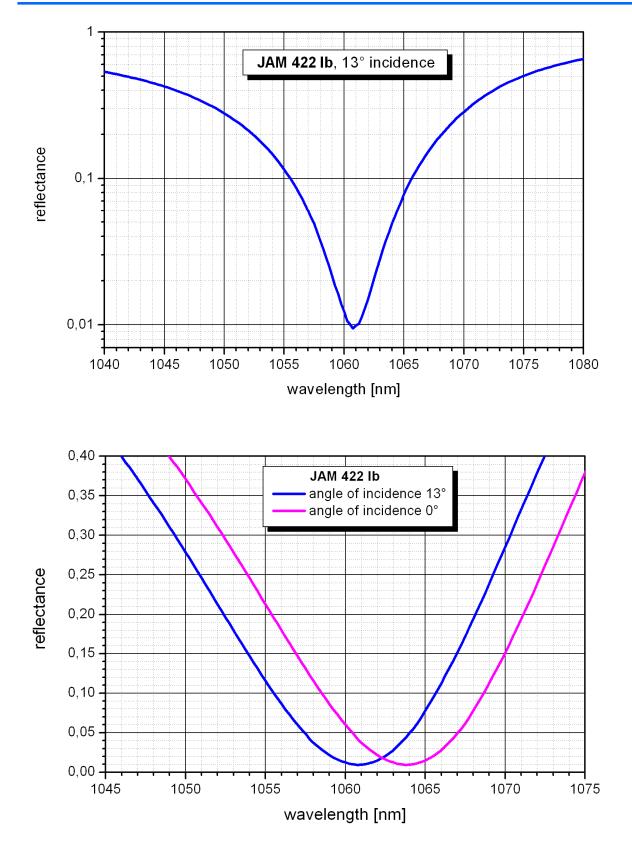
RSAM - Resonant saturable absorber mirror

Working wavelength Full Width at Half Maximum Low intensity absorptance Low intensity reflectance	λ = 10501064 nm (angle and temperature dependent) FWHM = 25 nm A = 99 % R_min \leq 1 %
Saturation fluence	$\Phi_{sat} = 15 \ \mu J/cm^2$
Relaxation time constant	τ ~ 9 ps
Non-saturable loss	$A_{ns} \sim 40$ %, depending on the pulse duration
Chip area	4.0 mm x 4.0 mm; other dimensions on request
Chip thickness	450 μm
Front side	dielectric cover
Mounting of RSAM-1064-x x = 0 x = 12.7 g x = 25.4 g x = 12.7 s x = 25.4 s x = FC x = FC/PC with TEC	denotes the type of mounting as follows: unmounted glued on a gold plated Cu-cylinder with 12.7 mm Ø glued on a gold plated Cu-cylinder with 25.4 mm Ø soldered on a gold plated Cu-cylinder with 12.7 mm Ø soldered on a gold plated Cu-cylinder with 25.4 mm Ø mounted on a 1 m monomode fiber cable with FC/PC connector mounted on a 1 m monomode fiber cable with FC/PC or other connector type and TEC (thermoelectric cooler) for fine tuning of the resonance wavelength

Unsaturated spectral reflectance, measured at room temperature with 13° angle of incidence

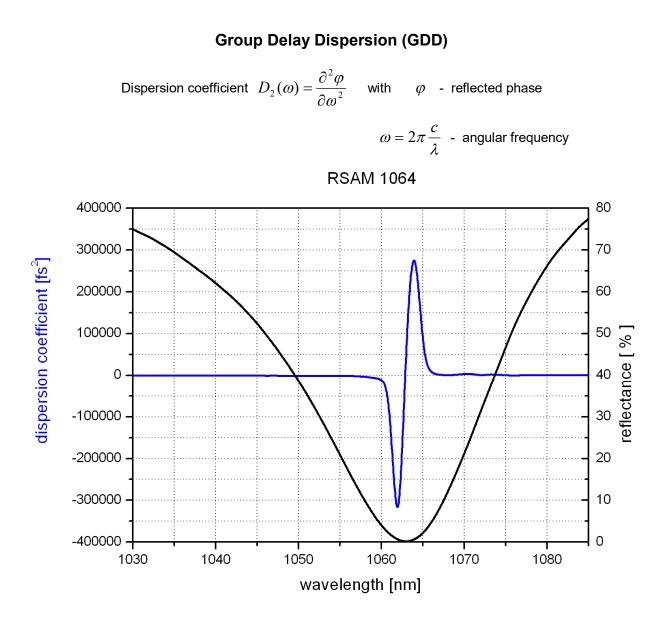








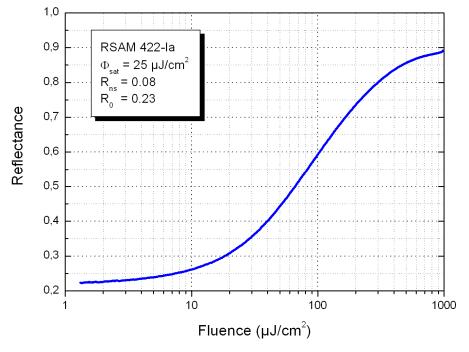
Dispersion:



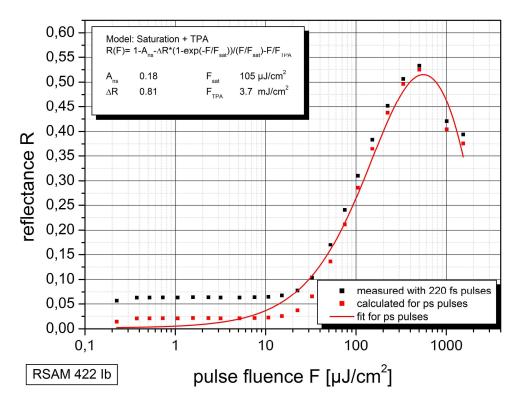


Saturation:

The reflectance depends on the input pulse fluence Φ_{i}

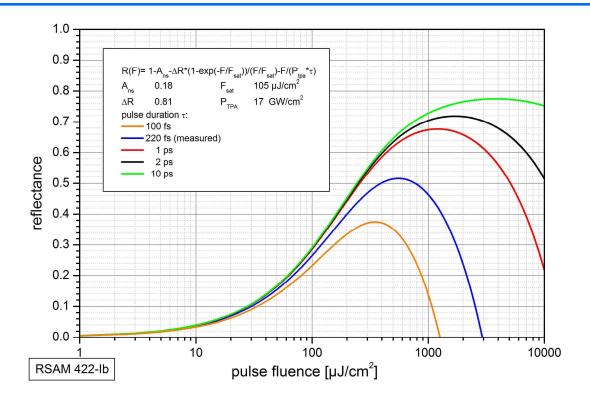


The measurement of the saturation with ps pulses has been carried out by D. Fischer and G. Steinmeyer, Max-Born-Institut Berlin, Germany on a sample with low intensity reflectance R_0 of 23 %.

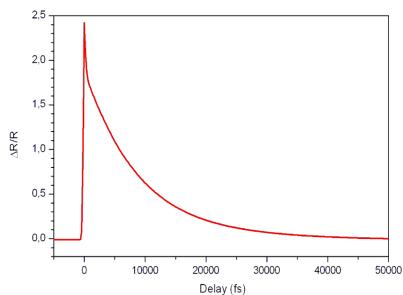


This saturation measurement has been done with 220 fs pulses, where the pulse spectral width of \sim 20 nm is as large as the spectral bandwidth. The red points are re-calculated for ps pulses. Due to the high peak power density of the fs pulses the TPA is significant.

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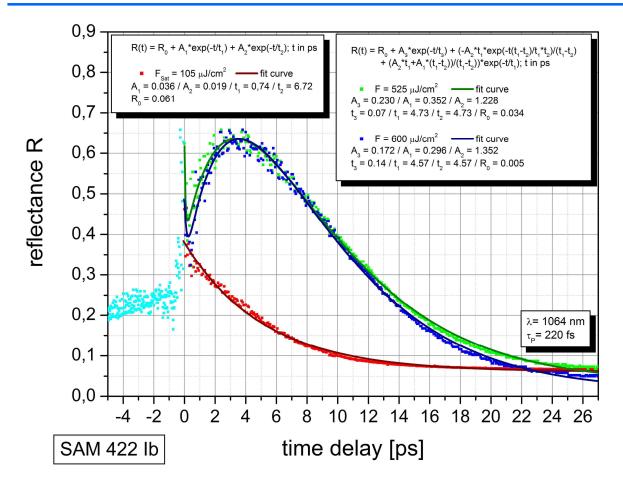
Calculated saturation curves for different pulse duration τ , based on the measured saturation above with a pulse duration of 220 fs. The non-saturable loss increases with decreasing pulse duration.



Relaxation time, measured in a pump-probe experiment by D. Fischer and G. Steinmeyer, Max-Born-Institut Berlin, Germany

Relaxation time





Relaxation time measurement with 220 fs pulses

Resonance wavelength λ

Angle of incidence φ

The resonance wavelength λ of the RSAM depends on the angle of incidence ϕ as

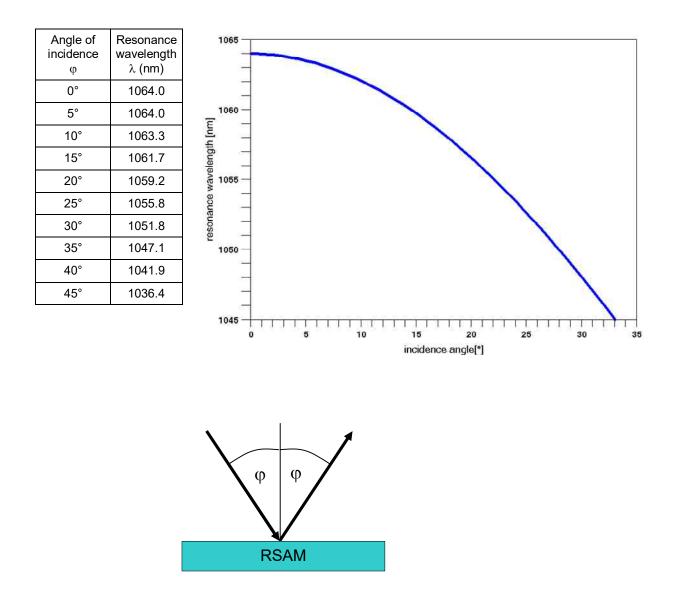
$$\lambda(\varphi) = \lambda_0 \sqrt{1 - \frac{\sin^2 \varphi}{n^2}} \tag{1}$$

The zero resonance wavelength λ_0 is determined by the index of refraction n and the geometrical thickness d of the absorbing spacer layer inside the Gires–Tournois interferometer by

$$\lambda_0 = 2nd. \tag{2}$$

To adjust the working wavelength to the resonance wavelength λ of the RSAM the angle of incidence ϕ has to be chosen according to equation (1) with λ_0 = 1064 nm and n = 2.9.





Temperature T

The temperature dependency of the optical thickness nd of the absorbing spacer layer, which governs the resonance wavelength λ , is mainly determined by the temperature dependency of the refractive index n(T). The thermal expansion of the spacer layer thickness d is negligible in comparison with the temperature influence on the refractive index.

The resulting temperature dependency of the resonance wavelength $\boldsymbol{\lambda}$ is given by

$$\lambda(T) = \lambda(T_0) \left[1 + \frac{1}{n} \frac{dn}{dT} (T - T_0) \right]$$
(3)

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with

temperature coefficient
$$\frac{1}{n} \frac{dn}{dT} \approx 7.5 \cdot 10^{-5} K^{-1}$$

T₀ - reference temperature

T – working temperature.

In case of a fiber coupled RSAM the angle of incidence is fixed to $\varphi = 0^{\circ}$. To adjust in this case the working wavelength to the resonance wavelength a thermoelectric cooler (TEC) or heater can be used.

